

68th Conference Technical Agenda Selections

- **Invited Talk:** *Which EM Analysis Should I Use?*, James Rautio (IEEE Distinguished Microwave Lecturer)
- *Traceability to National Standards for S-parameter Measurements of Devices Fitted with Precision 1.85 mm Coaxial Connectors*, Nick M Ridler, National Physical Laboratory
- *RF Vector Measurement Test-Bench for Behavioral Model's Accuracy Evaluation under Realistic Excitation*, Maciej Myslinski, ¹K.U.Leuven
- *Terminology for High-Speed Sampling-Oscilloscope Calibration*, Dylan Williams, NIST
- *In-Phase/Quadrature Covariance-Matrix Representation of the Uncertainty of Vectors and Complex Numbers*, Dylan Williams, NIST
- *A New Scalar Microwave Interferometric Measurement System*, Jan Zela, Czech Technical University in Prague
- *A Behavioral Power Amplifier Model That Includes The Average Power Level*, David Wisell¹, University of Gävle and Ericsson AB
- *True Pulse Load-Pull Measurement Setup for High Power Transistors Characterization*, JM Coupat, Freescale Semiconductor Inc.
- *A Pulsed Network Analyzer for High Dynamic Range Isothermal Measurements*, M. Marchetti, Delft University of Technology
- *Validation of On-Wafer Vector Network Analyzer Systems*, J. Randy Fenton, Cascade Microtech, Inc.,
- *Load-pull measurement of transistor negative input impedance*, Fabien DeGroote, XLIM- CNRS University of Limoges
- *Real-time Active Load-pull of the 2nd & 3rd Harmonics for Interactive Design of Non-linear Power Amplifier*, Xian Cui, Ohio State University
- *A Hybrid Probe-Tip Calibration for Multiport Vector Network Analyzers*, Leonard Hayden, Cascade Microtech, Inc.
- *Re-visiting the Repeatability Issues of the type-N Connectors*, Yeou-Song (Brian) Lee, Anritsu Company



68th ARFTG Microwave Measurement Symposium

Measurement for Emerging Technologies

Broomfield, Colorado

November 28 to December 1, 2006

Conference Chair:
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Nonlinear Measurement
Workshop:
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ARFTG will hold its 68th Microwave Measurement Conference at the Omni Interlocken Resort in Broomfield, CO. Join us as we explore the new **microwave measurement methodologies and techniques required by emerging technologies.**



Join us in a practical microwave measurement tutorial, intended for engineers, experienced technicians, or technical managers. **Day 1:** VNA error models, calibration and uncertainty; RF connectors; on-wafer measurements; power; thermal noise; phase noise; **Day 2:** uncertainty analysis for complex quantities; introduction to optoelectronic measurements; practical oscilloscope measurements. **Space is limited; please register early!**



Many instruments used in nonlinear measurement are based on RF samplers, including oscilloscopes, LSNAs/MTAs, some VNAs and spectrum analyzers. We will discuss the advantages and weaknesses of high-frequency sampling compared to traditional RF mixing for measurements, especially in the case of large signals. Along with highlights on up-to-date very fast sampling technologies, we will discuss some more exotic techniques with surprising results and impressive capabilities.



Omni Interlocken Resort
500 Interlocken Blvd.
Broomfield (Near Boulder), CO 80021
Phone: +1-303-438-6600, Fax: +1-303-438-7224

All sessions will be held at the Omni Interlocken Resort

Reserve your hotel room at the Omni by Nov. 5th to guarantee your lodging. Mention ARFTG to qualify for the special conference rate of \$93 per night.

Special Awards Banquet Presentation:

Celebrating the 175th Anniversary of the Birth of James Clerk Maxwell

James Rautio: IEEE Distinguished Microwave Lecturer



NIST/ARFTG Measurement Short Course	Tuesday, Nov. 28 8:00 am – 5:00 pm Wednesday, Nov. 29 8:00 am – noon
Nonlinear Workshop	Wednesday, Nov. 29 1:00 pm – 5:00 pm
NVNA Users' Forum	Wednesday, Nov. 29 5:00 pm – 7:00 pm
ARFTG Microwave Measurement Conference	Thursday, Nov. 30 8:00 am – 5:00 pm Friday, Dec. 1 8:00 am – noon
Reception and Awards Banquet	Thursday, Nov. 30 Approx. 6pm till 10 pm
Tour at NIST	Friday, Dec. 1 1:30 pm – 3:00 pm

Registration Form

Last Name _____

First Name _____

Company _____

Mail Stop _____

Address _____

City _____ State _____ Zip _____

Country _____

Phone _____

Fax _____

Email _____

Registration:

NIST/ARFTG Short Course \$450 \$ _____

68th ARFTG Conference \$460 \$ _____

Non-Linear Workshop only \$150 \$ _____

(no additional fee for Workshop if registered for either the Short Course or the Conference)

Payment Total: \$ _____

Check (payable to ARFTG, US dollars on US Bank)

Credit Card: __ Visa __ MC __ AMEX

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Registration forms for both Exhibitors and Participants are also available online at: <http://www.arftg.org>